

[本期目录](#) | [下期目录](#) | [过刊浏览](#) | [高级检索](#)[\[打印本页\]](#) [\[关闭\]](#)

器件制备技术及器件物理

基于溶液法的规则排列连续晶畴的金属诱导多晶硅薄膜及薄膜晶体管

赵淑云¹;孟志国^{1,2};王文¹;郭海成¹

1. 香港科技大学 电子及计算机工程系, 香港 九龙; 2. 南开大学 光电子所, 天津 300071

摘要: 介绍了一种新的金属诱导多晶硅技术。该技术的核心是预设规则化晶核定位孔和镍源补充孔与溶液浸蘸技术的结合。以定位孔为晶化的起始点, 晶化过程中消耗的镍可通过分布在周边的镍源补充孔中的镍给予补充。这样可以大大降低晶核定位孔中的初始镍量, 使整个多晶硅薄膜中不存在明显的高镍含量区。即包括晶核定位孔、镍源补充孔在内的整个多晶硅薄膜区域内, 能形成连续晶畴的多晶硅薄膜, 都可作为高质量TFT的有源层。根据晶核定位孔分布形式的不同, 可以设计成规则、重复的分布形式, 获得正六边形的蜂巢晶体薄膜和准平行晶带晶体薄膜。这些规则形成的晶畴形状与尺寸相同, 可准确地控制晶化的过程, 具〔JP2〕有晶化时间的高可控性和工艺过程的高稳定性, 故而适合于工业化生产的要求。利用些技术, 当温度为590℃〔JP〕时, 可将晶化时间缩短至2h之内。用这种多晶硅薄膜为有源层, 所得多晶硅TFT的场效应迁移率典型值为 $\sim 55 \text{ cm}^2/\text{V} \cdot \text{s}$, 亚阈值斜摆幅为0.6 V/dec, 开关电流比为 $\sim 1 \times 10^7$, 开启电压为-3 V。

关键词: 金属诱导晶化 规则排列连续晶畴 薄膜晶体管 低温多晶硅

Defined Grain Polycrystalline Thin Film Transistors Using Solution Based Metal Induced Crystallization

ZHAO Shu-yun¹; MENG Zhi-guo^{1,2}; WONG man¹; KWOK Hoi-sing¹

1. Department of Electronic and Computer Engineering, Hong Kong University of Science and Technology, Hong Kong, China; 2. Institute of Opto-Electronics, Nankai University, Tianjin 300071, China

Abstract: A new technique has been proposed to define and control the grain boundaries and domains of low temperature polycrystalline silicon (LTPS) films. It can be realized by combination of the solution process and the provision of nucleation sites (NS) and supplemental sites (SS). As a result, the crystallized poly-Si film has a much lower nickel concentration as compared to traditional metal induced lateral crystallization (MILC) poly-Si. High performance TFTs are obtained regardless of the position of the grain boundaries. Different shapes of domains can be obtained corresponding to different distributions of the NS and SS. Among the optimal designs, a honeycomb-like structure and a unidirectional structure are the most typical and practical. With the repeatedly regular distribution of the NS and the SS, domains of the same shape and size can be achieved. This process is precisely controllable and the crystallization time can be reduced to about 2 h at the annealing temperature of 590 °C. The fabricated P-channel defined-grain (DG) poly-Si TFTs exhibited a maximum field effect mobility (μ_{FE}) of $\sim 55 \text{ cm}^2/\text{V} \cdot \text{s}$, a subthreshold swing (S) of $\sim 0.6 \text{ V/dec}$ and a threshold voltage (V_{th}) of -3 V. The ratio of on-state to off-state drain currents is $\sim 1 \times 10^7$.

Keywords: metal induced crystallization defined-grain polycrystalline thin film transistor LTPS

收稿日期 2009-07-30 修回日期 1900-01-01 网络版发布日期 2010-06-30

基金项目:

通讯作者:

作者简介:

作者Email:

参考文献:

- [1] Jin Z, Bhat G A, Yeung M, *et al.* Nickel induced crystallization of amorphous silicon thin film [J]. *J. Appl. Phys.*, 1998, 84(1): 194-200.
- [2] Jang J, Park S J, Kim K H, *et al.* Polycrystalline silicon reduced by Ni-silicide mediated crystallization of amorphous silicon in an electric field [J]. *J. Appl. Phys.*, 2000, 88(5): 3099-3101.
- [3] Kubo N, Kusumoto N, Inushima T, *et al.* Characteristics of polycrystalline-Si thin film transistors fabricated by excimer laser annealing method [J]. *IEEE Transactions on Electron Devices*, 1994, 41(10): 1876-1879.
- [4] Lee S W, Joo S K. Low temperature poly-Si thin-film transistor fabrication by metal-induced lateral crystallization [J]. *IEEE Electron Devices Letters*, 1996, 17(4): 160-162.
- [5] Meng Z G, Wong M. Active-matrix organic light-emitting diode displays realized using metal-induced unilaterally crystallized polycrystalline silicon thin-film transistors [J]. *IEEE Transactions on Electron Devices*, 2002, 49(6): 991-996.
- [6] Choi J H, Cheon J H, Kim S K, *et al.* Giant-grain silicon (GGS) and its application to stable thin-film transistor [J]. *Displays*, 2005, 26: 137-142.
- [7] Meng Z G, Zhao S, Wu C, *et al.* Polycrystalline silicon films and thin-film transistors using solution-based metal-induced crystallization [J]. *J. Display Technology*, 2006, 2(3): 265-273.

本刊中的类似文章

1. 何慧, 王刚, 赵谏玲, 刘则, 侯文军, 代青, 徐征. 有机绝缘层材料聚(4-乙炔基苯酚)喷墨打印工艺研究[J]. 液晶与显示, 2012, (5): 590-594
2. 陈世琴, 陈梦婕, 邱龙臻. 石墨烯电极有机薄膜晶体管研究[J]. 液晶与显示, 2012, (5): 595-598
3. 洪飞, 谭莉, 朱棋峰, 向长江, 韩学斌, 张其国, 郭晓东, 申剑锋. 高性能顶栅结构有机薄膜晶体管[J]. 液晶与显示, 2012, (3): 313-317
4. 彭尚龙, 胡多凯, 贺德衍. 镍硅化物诱导横向晶化制备高性能多晶硅薄膜晶体管[J]. 液晶与显示, 2012, (3): 303-307

5. 孙长辉, 李灿灿, 王情伟, 李丰果. TFT-LCD三基色光谱的温度特性[J]. 液晶与显示, 2011,26(6): 746-749
6. 曲连杰, 陈旭, 郭建, 闵泰焯, 谢振宇, 张文余. 氮化硅在触摸屏中的应用分析[J]. 液晶与显示, 2011,(4): 466-470
7. 邓婉玲. 多晶硅薄膜晶体管的栅电容模型[J]. 液晶与显示, 2011,26(2): 178-182
8. 刘远, 姚若河, 李斌. 非晶硅薄膜晶体管的热阻模型[J]. 液晶与显示, 2011,26(1): 28-33
9. 周伟峰, 薛建设, 明星, 刘翔, 郭建, 谢振宇, 赵承潭, 陈旭, 闵泰焯. 应用低介电材料丙烯酸酯树脂作为 TFT-LCD的钝化层材料[J]. 液晶与显示, 2011,26(1): 19-22
10. 马舜峰, 金龙旭, 安少婷, 朴永杰, 张柯, 陶宏江. 一种基于ARM9的彩色TFT-LCD模块设计及实现[J]. 液晶与显示, 2010,25(5): 718-723
11. 李桂锋, 冯佳涵, 周俊, 张群. 有机介质层铟锌氧化物薄膜晶体管[J]. 液晶与显示, 2010,25(4): 558-560
12. 姚绮君, 李曙新, 张群. 基于In-Zn-Ti-O氧化物半导体材料的薄膜晶体管[J]. 液晶与显示, 2010,25(4): 569-571
13. 徐小丽, 刘如, 郭小军, 苏翼凯. 基于不同TFT技术的AMOLED像素电路仿真分析[J]. 液晶与显示, 2010,25(4): 565-568
14. 吴为敬. 多晶硅薄膜晶体管亚阈值区准二维模型[J]. 液晶与显示, 2010,25(4): 523-526
15. 张平, 胡文华, 景亚霓, 唐正宁, 钟传杰. 喷墨印刷制备有机薄膜晶体管及其电路的研究进展[J]. 液晶与显示, 2010,25(1): 34-39